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In the specification:

Please replace paragraph [0039] with the following rewritten paragraph:

FIG. 4 shows, by contrast with FIG. 3, the illumination PSF of the double confocal scanning microscope when optical component 24 is arranged, in accordance with the present invention, in the illuminating beam path. Here again, the normalized intensity of the illuminating light is shown as a function of the local coordinate along optical axis 27 (Z direction). According to the present invention, optical component 24 is configured in such a way that it influences the amplitude and phase of the illuminating light, thereby modifying the characteristics of the double confocal illumination. It is thus evident from FIG. 4 that the shape of the double confocal illumination PSF is modified, as compared to the shape of the illumination PSF of FIG. 3, by optical component 24. It may furthermore be gathered from FIG. 4 that a principal maximum with a normalized intensity value of 1 is present at the Z coordinate 300. This principal maximum exhibits a slightly broadened FWHM (full width at half maximum) compared to the principal maximum of FIG. 3. Also evident alongside the principal maximum of FIG. 4 are several secondary maxima, in particular the two secondary maxima adjacent to the principal maximum at Z coordinates of approximately 210 and [290] 390 These two secondary maxima are modified in shape compared to the two secondary maxima of FIG. 3. Their position is also different as compared to the illumination PSF of FIG. 3. Two further respective secondary maxima are moreover also evident, two secondary maxima with a normalized intensity value of approx. 0.9 being arranged at Z coordinates of approximately 150 and 450, respectively. The two secondary maxima with a normalized intensity value of approximately 0.25 are arranged at the Z coordinates 50 and 550.

B4